



CetisPV-Celltest4-BF

Class AAA+ high-precision lab tester to measure bifacial (BF) solar cells

CetisPV-Celltest4-BF provides the possibility to measure monofacial and bifacial solar cells using different illumination levels for their rear and front side. Using two synchronized class AAA+ Xenon flashers, flexible flash profiles can be applied within one measurement sequence. This enables the measurement under front and rear STC conditions, as well as typical field conditions for bifacial solar (e.g. 1.000Wm²(front) and 200Wm²(rear)).

CetisPV-Celltest4-BF is designed for high-end R&D, laboratory and quality control demands. Its solar simulator provides a highly stable irradiance overlong flash duration. Combined with the well-known halm IV curve tracer and halm single-flash advanced hysteresis to measure high-capacitance solar, this system is designed to match the demands of current and up-coming cell technologies. Our applicant software PVControl offers one-click solutions for parameter adaptions and the recipe-based storage of settings, including polarity switching and customized evaluations using user-defined formulas.

The standard IV measurement system can be complemented by further tools for quality and process control such as electroluminescence or infrared imaging, in line spectral response and grid resistance.

Technical Specifications					
Sun Simulator					
Irradiance	200 1.100Wm ²				
Illumination area	≥240mm X 240mm				
Flash duration (bifacial)	Rear: 1.000Wm ²	200Wm²			
	Front:	1.000Wm ²	1.000W	m²	
	Up to 3 x 40 ms:	40ms	40ms	40ms	
	With a repetition ra	ate of 4 s			
	Up to 3 x 60 ms ¹ :	60ms	60ms	60ms	
	With an additional	power booste	r cetisPV-XF	3-PB and a repetition rate of 8 s	5
Flash profiles	Single level for star	Single level for standard IV curve, intensity ramp for SunsVoc option only			
	monofacial: double	or triple leve	for series r	esistance determination accordi	ing
	to IEC 60891				
Spectral match ²	Front: 0,875 – 1,12	5 at 1.000 Wn	n² (class A+)	/ rear: 0,75 – 1,25 (class A)	
Non-uniformity of irradiance ²	<2 %³ at 1.000Wm²	^e (class A)			
Short-term instability of irradian	ce ² <0,05 % at 1.000W	m² (class A+ ≤	0,25 %)		
Long-term instability of irradian	ce ² <0,08 % at 1.000W	m² (class A+ ≤	1 %)		
Guaranteed lamp lifetime	Up to 2 years for fla	ashes with a fl	sh duration	of 80ms or 3 x 40 ms and a	
	repetition rate of 4	S			
Lamp type	Xenon tube				
¹ Preliminary	² IEC 60904-9:2020 Ed 3	³ n	neasured w	ithout contact bars	
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Measurement system	
IV measurement types	Light forward, dark revers, dark forward (low current9, dark forward (high current), advanced hysteresis, measured IV curve can be exported in ASCII format (optional: SunsVoc, 2-diode analysis
Repeatability ⁴	lsc, Voc: σ < 0,1 % / Pmpp FF: σ < 0,15 %
Measurement resolution	< 0,0004 % FSR (4 synchronous 16-bit channels for voltage, current, and 2 x irradiance
Measurement accuracy	< 0,05 % FSR for current and voltage measurements
Voltage measurement ranges	± 1 V / ± 2 V / ±4 V / ±10 V / ± 16 V / or ± 1 V / ± 2 V / ±4 V / ±10 V / ± 120 V / + 12V
Current measurement ranges	$\frac{\pm 2,5 \text{ V} \pm 5 \text{ V} \pm 12,5 \text{ V} \pm 25 \text{ A}}{\pm 16 \text{ mA} \pm 32 \text{ mA} \pm 80 \text{ mA} \pm 160 \text{ mA}}$
Measurement points	Up to 1,024 for every type of measurement
Measurement parameters (subset of more than 500 available parameters	Bifacial Isc, bifacial Voc, Bifacial Eta, bifacial Pmpp, bifaciality coefficients Isc (short – circuit current), Jsc (Short-circuit current density), Uoc (open-circuit voltage), FF (fill factor), Eta (efficiency), Pmpp (maximum power), Impp (current at maximum power point), Jmpp (current density at maximum power point), Vmpp (voltage at maximum power point), series and shunt resistance (various determination methods), Irev (reverse current)
Irradiance sensor	Encapsulated 20 mm x 20 mm crystalline Si cell including integrated temperature sensor Measurement certificate for linearity with respect to irradiance and temperature coefficient
Temperature measurement	Contactless temperature measurements using a pyrometer
	Repeatability: ± 0,5 K
Electronic load	Active 4-quadrant load
System calibration	Calibration with calibrated reference solar cell (reference cells not included)
Conacting station	
Feature	Hand-operated bifacial contacting station
Solar cell layouts	From 150 mm x 156 mm up to 220 mm x 220 mm
Operation control system	
Software features	Fully controlled measurement procedures and evaluations
	Automatic calibration
	Classification with up to 256 BINs
Recipes managements for	Measurement types
	Cell types
	Calibration cells
	Flash profiles
GUI feautres	Customizable display of measurement results
	Display of device status
Data storage	Database support for MySQL, ACCESS, MS-SQL, Postgres
	ASCII files for raw curve data
Measurement PC	PC, 8 GB Ram, 2x2 TB hard disk (RAID), 19" monitor, keyboard, mouse, Windows 10 (English)

⁴ FAT repeatability tests test is if the relative standard deviation σ of 20 measurements without recontacting of the cell is less than standard deviation.

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General information	
Dimensions	Dark chamber with contacting station and flash boxes
	_ (880 mm x 780 mm x 2.400 mm)
	Control cabinet (550 mm x 780 mm x 1.675 mm) or
	2 x (550 mm x 780 mm x 1.300 mm)
Weight	Dark chamber with contacting station (<170 Kg)
Noise level	Control cabinet 70dB (A)
Power requirements	3-Phase (3L + N + PE) 400 Vac ± 10 % / 50 or 60 Hz ± 1 % ; 10kVA; 16 A (Slow-
	blow fuse) ⁵
Required ambiance conditions	Indoor use only at or below 2.000m AMSL
	15°C – 35°C; 0 % 80% Relative humidity (noncondensing)
Documentation	User Manuel (English)
Certification for solar simulator	Spectrum measurement, non-uniformity measurement, temporal stability
(IEC 60904-9:2020 Ed. 3)	measurement
Calibration certification	Factory calibration protocol for measurement channels: I, V, irradiance,
	temperature

⁵ fuse protection depending on requirements and statutory regulations at set-up location.

Dimensions and integration of the CetisPV-Celltest4-BF

CetisPV-Celltest4-BF consists of a dark chamber with 2 flasher units and contacting station as well as the curve trace, the measurement PC and units to control the sun simulator.





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